



17th IEEE European Test Symposium

ANNECY, FRANCE - IMPERIAL PALACE

May 28th - June 1st, 2012

<http://ets2012.imag.fr>

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Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics and new trends in the area of electronic-based circuits and system testing. A Test Spring School will be organized in conjunction with ETS'12.

In 2012 ETS will take place in Imperial Palace, Annecy, France and is being organized by TIMA Laboratory (CNRS, Grenoble INP, UJF) and sponsored by the Test Technology Technical Council of the IEEE Computer Society.

TOPICS

You are invited to participate and submit contributions to ETS'12. The areas of interest include (but are not limited to) the following topics.

- Analog Test
- ATE Hardware and Software
- Automatic Test Generation
- Board Test and Diagnosis
- Boundary Scan Test
- Built-In Self Test (BIST)
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability
- Design for Test(ability) - DfT
- Design Verification and Validation
- Diagnosis and Debug
- Economics of Test
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- High-Speed I/O Test
- Memory Test and Repair
- MEMS Test
- Microprocessor Test
- Mixed-Signal Test
- Nanotechnology Test
- On-line Test
- Power Issues in Test
- Reliability
- RF Test
- Self-Repair
- Signal Integrity Test
- Stacked IC Test
- Standards in Test
- System Test
- System-in-Package (SiP) Test
- System-on-Chip (SoC) Test
- Soft Errors
- Test(ability) Synthesis
- Test of Reconfigurable Systems
- Test Quality
- Thermal Issues in Test
- Yield Analysis and Enhancement

PUBLICATIONS

ETS'12 will produce Formal Proceedings of selected papers and an Informal Digest of Papers. The best contributions will be selected for submission to regular issues of the «Journal of Electronic Testing: Theory and Applications» (JETTA), published by Springer and IEEE Design & Test of Computers. A Best Paper Award of ETS'12 will be presented at ETS'13.

SUBMISSIONS

ETS'12 seeks original, unpublished contributions of the following types:

- **Scientific papers** for the Formal Proceedings, presenting novel and complete research work.
- **Workshop-type papers** for the Informal Digest, including «emerging ideas» and «case studies».
- **Proposals for panels, embedded tutorials, and other special sessions.**
- **Vendor presentations** focusing on new features of test related products.
- **Student work-in-progress** presenting on-going and not yet complete work.
- **Doctoral student contest** is open for doctoral students in their final year.

Detailed submission instructions, including selection criteria and publication policies, for the various types of contributions are posted on the ETS'12 web page.

The ETS'12 organizing committee also encourages the organization of fringe meetings and workshops. Visit ETS'12 web page at: <http://ets2012.imag.fr> for more information.

KEY DATES

Paper submission deadline: Dec. 5th, 2011

Notification of acceptance: Feb. 17th, 2012

Camera-ready manuscript: Apr. 2nd, 2012

OTHER SUBMISSION DATES

Doctoral student contest: Feb. 24th, 2012

Vendor & special sessions: Jan. 27th, 2012

Student work-in-progress: Apr. 14th, 2012

VENUE

Annecy is a magnificent, very rich and well preserved historical city located in french Northern Alps, at the crossroad of great routes from Italy to Geneva. From its dense history, Annecy has preserved some beautiful buildings which permanently enriched the heritage of the city. The Lake of Annecy becomes the symbol of the city, as well as Thion, a former industrial route that has become tourist attraction. Surrounded by impressive Aravis and Veryrier high altitude French Alps, Annecy is nowadays an elegant and sophisticated lakeside resort with a pleasant port and beaches.



FURTHER INFORMATION

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